



FOR IMMEDIATE RELEASE

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**AEHR TEST SYSTEMS TO CELEBRATE SILVER ANNIVERSARY
AS IT EXHIBITS AT SEMICON WEST**

FREMONT, CA. (July 16, 2002) - Aehr Test Systems (Nasdaq: [AEHR](#)), a leading supplier of test and burn-in equipment to semiconductor manufacturers, today announced that this month marks the 25th anniversary of the founding of the Company, which will exhibit several of its products at Semicon West July 17-19, 2002, at the San Jose Convention Center in San Jose, CA.

Rhea Posedel, founder and chief executive officer of Aehr Test, said, "I am truly grateful for these 25 years of success in business since shipment of our first burn-in and test system in 1977. I can confidently say that we have done whatever it took to address the needs of semiconductor manufacturers. Semicon has always been an event where you can get an accurate gauge of the present industry capabilities, so it is a place where our consistency as leaders of the industry has become known."

Chris Noe, vice president of worldwide sales, added, "As much as ever before, we are producing systems that are on the leading edge of this industry. Attendees of the show can see several systems that demonstrate this leadership."

At Semicon West, Aehr Test will be showing several of its newest systems, including two versions of the FOXTM full wafer contact burn-in and test system. Aehr Test will also be demonstrating the MAX4 low-voltage, high-power burn-in and test system.

The FOX system is designed to make contact with all pads of all die on a wafer simultaneously, thus enabling full wafer burn-in and parallel test. The unique design of the WaferPakTM cartridge system enables the FOX system to accommodate a wide range of applications. The WaferPak cartridge system and the FOX system's wafer aligner will also be on display at Semicon.

The MAX4 system is a low-voltage, high-power member of the MAX family of systems, which perform burn-in and test on memories, microprocessors, microcontrollers, digital signal processors and other ICs. The MAX is specially designed to make use of on-chip self test circuitry, such as BIST and structural test using JTAG.



Aehr Test Systems to Celebrate Silver Anniversary at Semicon West

July 16, 2002

Page 2

Aehr Test's DiePak® carriers, Performance Test Boards (PTBs) and BIBs will also be on display.

About Aehr Test Systems

Headquartered in Fremont, California, Aehr Test Systems is a leading provider of systems for burning-in and testing DRAM and logic integrated circuits and has an installed base of more than 2,000 systems worldwide. Aehr Test has developed and introduced several innovative products, including the FOX, MTX, MAX3 and MAX4 systems and the DiePak carrier. The FOX system is a full wafer contact burn-in and test system. The MTX system is a massively parallel test system designed to reduce the cost of memory testing by performing both test and burn-in on thousands of devices simultaneously. The MAX system can effectively burn-in and functionally test sophisticated devices, such as digital signal processors, microprocessors, microcontrollers and systems-on-a-chip. The DiePak carrier is a reusable, temporary package that enables IC manufacturers to perform cost-effective final test and burn-in of bare die.

Safe Harbor Statement

This release contains forward-looking statements that involve risks and uncertainties relating to projections regarding industry growth and customer demand for the Company's products. Actual results may vary from projected results. These risks and uncertainties include economic conditions in Asia and elsewhere, world events, acceptance by customers of the FOX, MTX, MAX and DiePak technologies, the Company's development and manufacture of a commercially successful wafer-level burn-in system, the Company's ability to meet engineering milestones, and the potential emergence of alternative technologies, which could adversely affect demand for the Company's products in fiscal year 2003. See the Company's latest 10-K and 10-Q reports filed with the SEC for additional risks affecting the Company.

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